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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	70
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-pl84c

ACT 3 Family Overview

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1 – ACT 3 Family Overview

General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

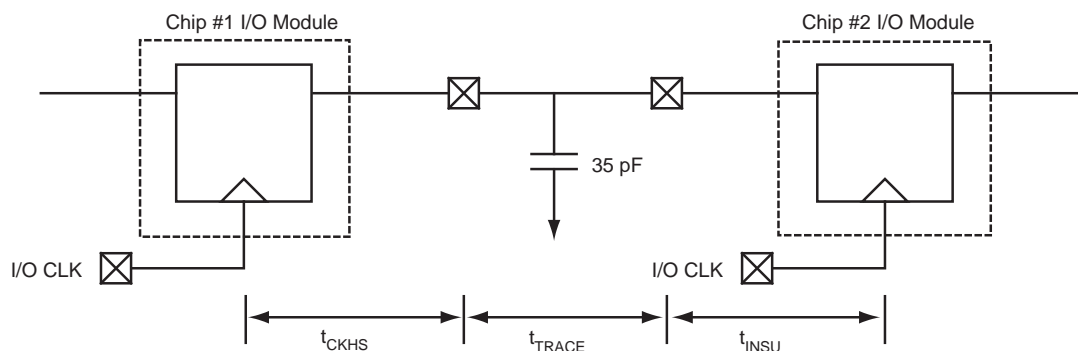
The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

Accumulators (16-Bit)	47 MHz
Loadable Counters (16-Bit)	82 MHz
Prescaled Loadable Counters (16-Bit)	186 MHz
Shift Registers	186 MHz

Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade)

System Performance Model



Logic Modules

ACT 3 logic modules are enhanced versions of the 1200XL family logic modules. As in the 1200XL family, there are two types of modules: C-modules and S-modules (Figure 2-2 and Figure 2-3). The C-module is functionally equivalent to the 1200XL C-module and implements high fanin combinatorial macros, such as 5-input AND, 5-input OR, and so on. It is available for use as the CM8 hard macro. The S-module is designed to implement high-speed sequential functions within a single module.

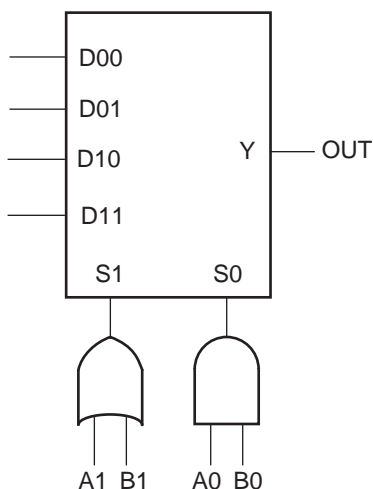


Figure 2-2 • C-Module Diagram

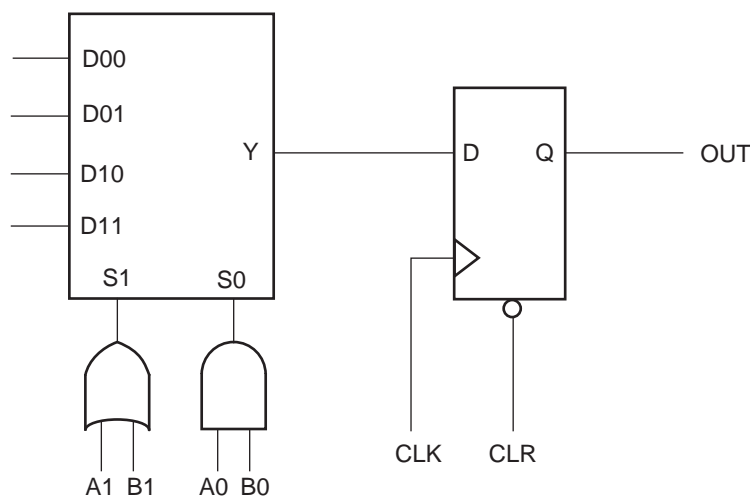


Figure 2-3 • S-Module Diagram

S-modules consist of a full C-module driving a flip-flop, which allows an additional level of logic to be implemented without additional propagation delay. It is available for use as the DFM8A/B and DLM8A/B hard macros. C-modules and S-modules are arranged in pairs called module-pairs. Module-pairs are arranged in alternating patterns and make up the bulk of the array. This arrangement allows the placement software to support two-module macros of four types (CC, CS, SC, and SS). The C-module implements the following function:

$$Y = !S1 * !S0 * D00 + !S1 * S0 * D01 + S1 * !S0 * D10 + S1 * S0 * D11$$

EQ 1

where: $S0 = A0 * B0$ and $S1 = A1 + B1$

Dedicated Clocks

Dedicated clock networks support high performance by providing sub-nanosecond skew and guaranteed performance. Dedicated clock networks contain no programming elements in the path from the I/O Pad Driver to the input of S-modules or I/O modules. There are two dedicated clock networks: one for the array registers (HCLK), and one for the I/O registers (IOCLK). The clock networks are accessed by special I/Os.

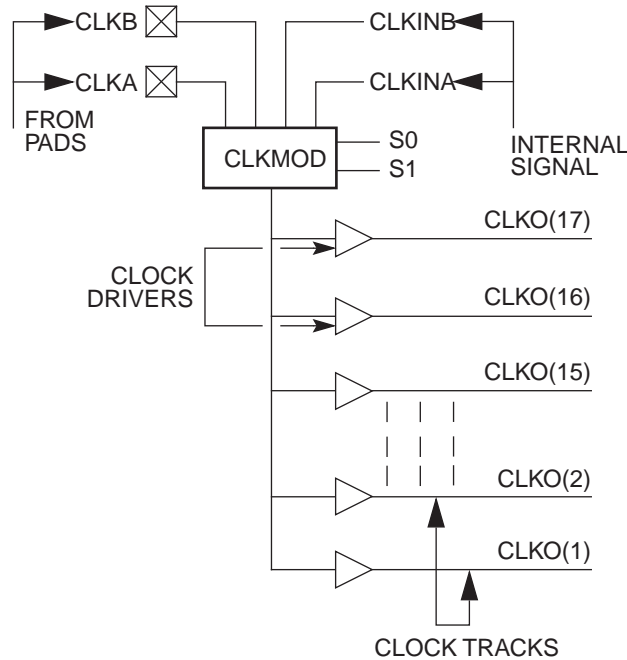


Figure 2-6 • Clock Networks

The routed clock networks are referred to as CLK0 and CLK1. Each network is connected to a clock module (CLKMOD) that selects the source of the clock signal and may be driven as follows (Figure 2-6):

- Externally from the CLKA pad
- Externally from the CLKB pad
- Internally from the CLKINA input
- Internally from the CLKINB input

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel. The function of the clock module is determined by the selection of clock macros from the macro library. The macro CLKBUF is used to connect one of the two external clock pins to a clock network, and the macro CLKINT is used to connect an internally generated clock signal to a clock network. Since both clock networks are identical, the user does not care whether CLK0 or CLK1 is being used. Routed clocks can also be used to drive high fanout nets like resets, output enables, or data enables. This saves logic modules and results in performance increases in some cases.

Routing Structure

The ACT 3 architecture uses vertical and horizontal routing tracks to connect the various logic and I/O modules. These routing tracks are metal interconnects that may either be of continuous length or broken into segments. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track.

5 V Operating Conditions

Table 2-2 • Absolute Maximum Ratings¹, Free Air Temperature Range

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current ²	±20	mA
T _{STG}	Storage temperature	–65 to +150	°C

Notes:

- Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.
- Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.

Table 2-3 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
5 V power supply tolerance	±5	±10	±10	%VCC

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 2-4 • Electrical Specifications

Symbol	Parameter	Test Condition	Commercial		Industrial		Military		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
VOH ^{1,2}	High level output	IOH = –4 mA (CMOS)	–	–	3.7	–	3.7	–	V
		IOH = –6 mA (CMOS)	3.84						V
		IOH = –10 mA (TTL) ³	2.40						V
VOL ^{1,2}	Low level output	IOL = +6 mA (CMOS)		0.33		0.4		0.4	V
		IOL = +12 mA (TTL) ³		0.50					
VIH	High level input	TTL inputs	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIL	Low level input	TTL inputs	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
IIN	Input leakage	VI = VCC or GND	–10	+10	–10	+10	–10	+10	μA
IOZ	3-state output leakage	VO = VCC or GND	–10	+10	–10	+10	–10	+10	μA
C _{IO}	I/O capacitance ^{3,4}			10		10		10	pF
ICC(S)	Standby VCC supply current (typical = 0.7 mA)			2		10		20	mA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.								

Notes:

- Microsemi devices can drive and receive either CMOS or TTL signal levels. No assignment of I/Os as TTL or CMOS is required.
- Tested one output at a time, VCC = minimum.
- Not tested; for information only.
- VOUT = 0 V, f = 1 MHz
- Typical standby current = 0.7 mA. All outputs unloaded. All inputs = VCC or GND.

Power Dissipation

$$P = [ICC_{\text{standby}} + I_{\text{active}}] * VCC * IOL * VOL * N + IOH * (VCC - VOH) * M$$

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in [Table 2-9](#) for commercial, worst case conditions.

Table 2-9 • Standby Power Calculation

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by [EQ 4](#).

$$\text{Power } (\mu\text{W}) = C_{\text{EQ}} * VCC^2 * F$$

EQ 4

Where:

C_{EQ} is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

A1425A, A14V25A Timing Characteristics (continued)

Table 2-23 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	1.8		2.0		2.3		2.7		3.0		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes: *

1. The –2 and –3 speed grades have been discontinued. Refer to [PDN 0104](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0203](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0604](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), and [PDN 1004](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn) at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1460A, A14V60A Timing Characteristics (continued)

Table 2-32 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.8		8.7		9.9		11.6		15.1	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.0		11.5		15.0	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing ¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.1		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to [PDN 0104](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0203](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0604](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), and [PDN 1004](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn) at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A1460A, A14V60A Timing Characteristics (continued)

Table 2-33 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

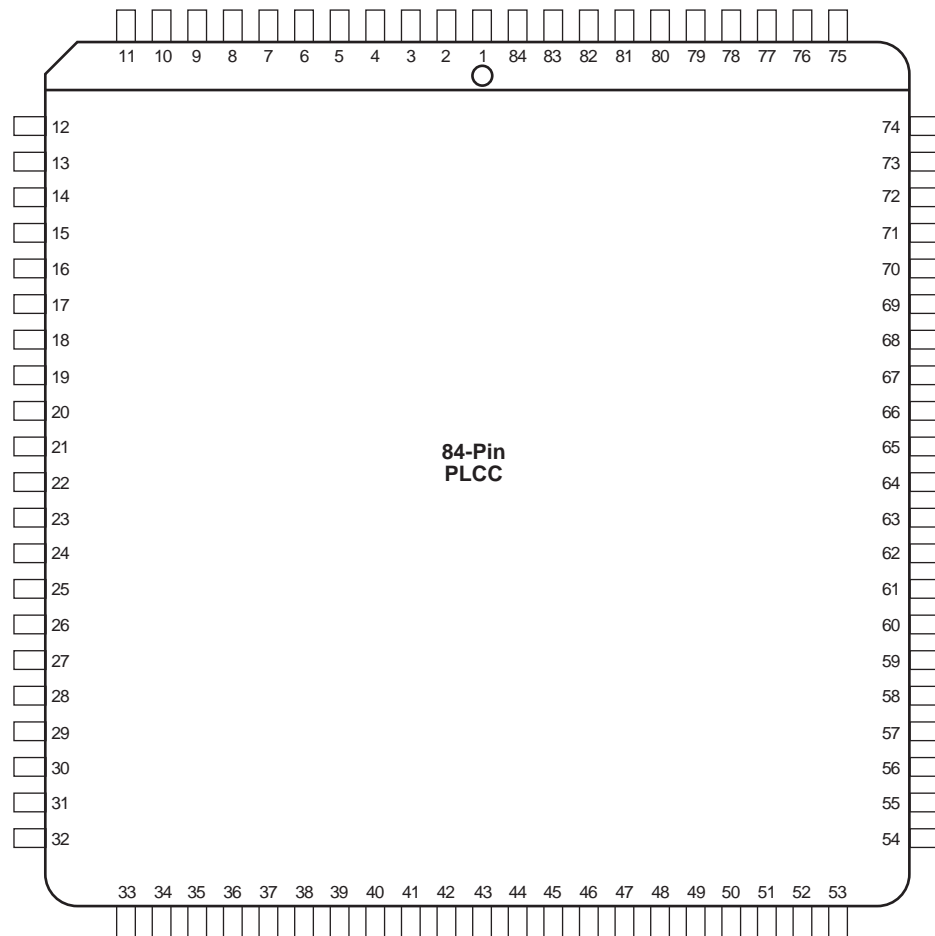
Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t _{IOPWH}	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t _{IPOWL}	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{ILOCKSW}	Maximum Skew		0.6		0.6		0.6		0.6		0.6	ns
t _{IOP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{IOMAX}	Maximum Frequency		200		150		125		100		75	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t _{HPWH}	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t _{HPWL}	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.6		0.6		0.6		0.6		0.6	ns
t _{HP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f _{HMAX}	Maximum Frequency		200		150		125		100		75	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RCKL}	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t _{RCKSW}	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t _{RP}	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f _{RMAX}	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.7	0.0	1.7	0.0	1.7	0.0	1.7	0.0	5.0	ns
		0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.3	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

- The –2 and –3 speed grades have been discontinued. Refer to [PDN 0104](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0203](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), [PDN 0604](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn), and [PDN 1004](http://www.microsemi.com/soc/support/notifications/default.aspx#pdn) at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
- Delays based on 35 pF loading.

3 – Package Pin Assignments

PL84

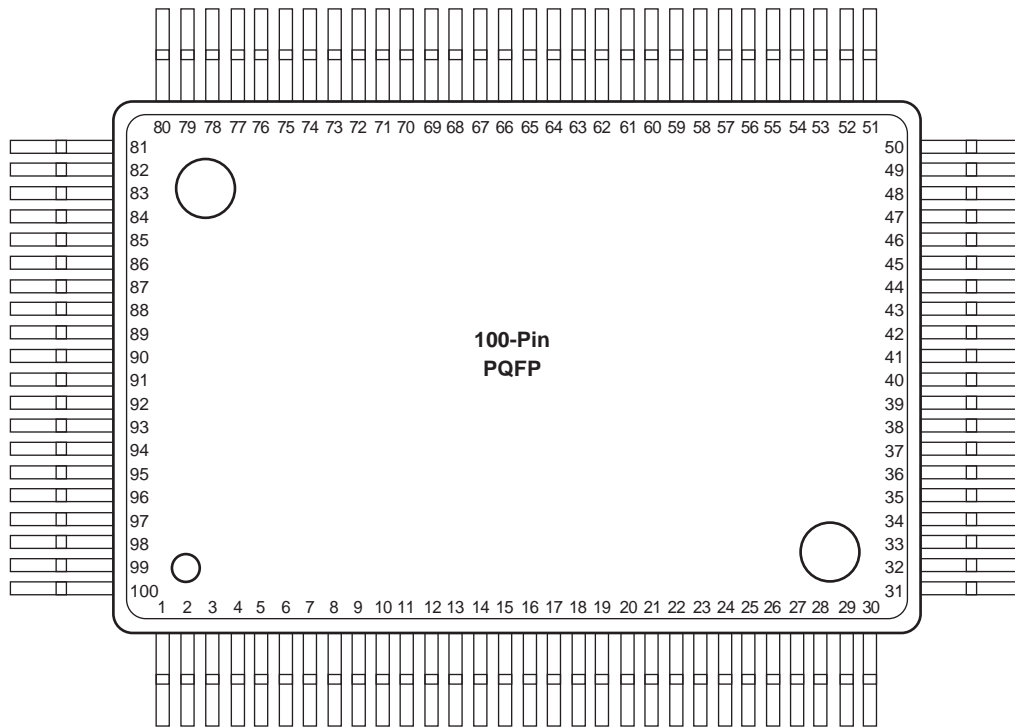


Note: This is the top view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

PQ100



Note: This is the top view of the package.

Note

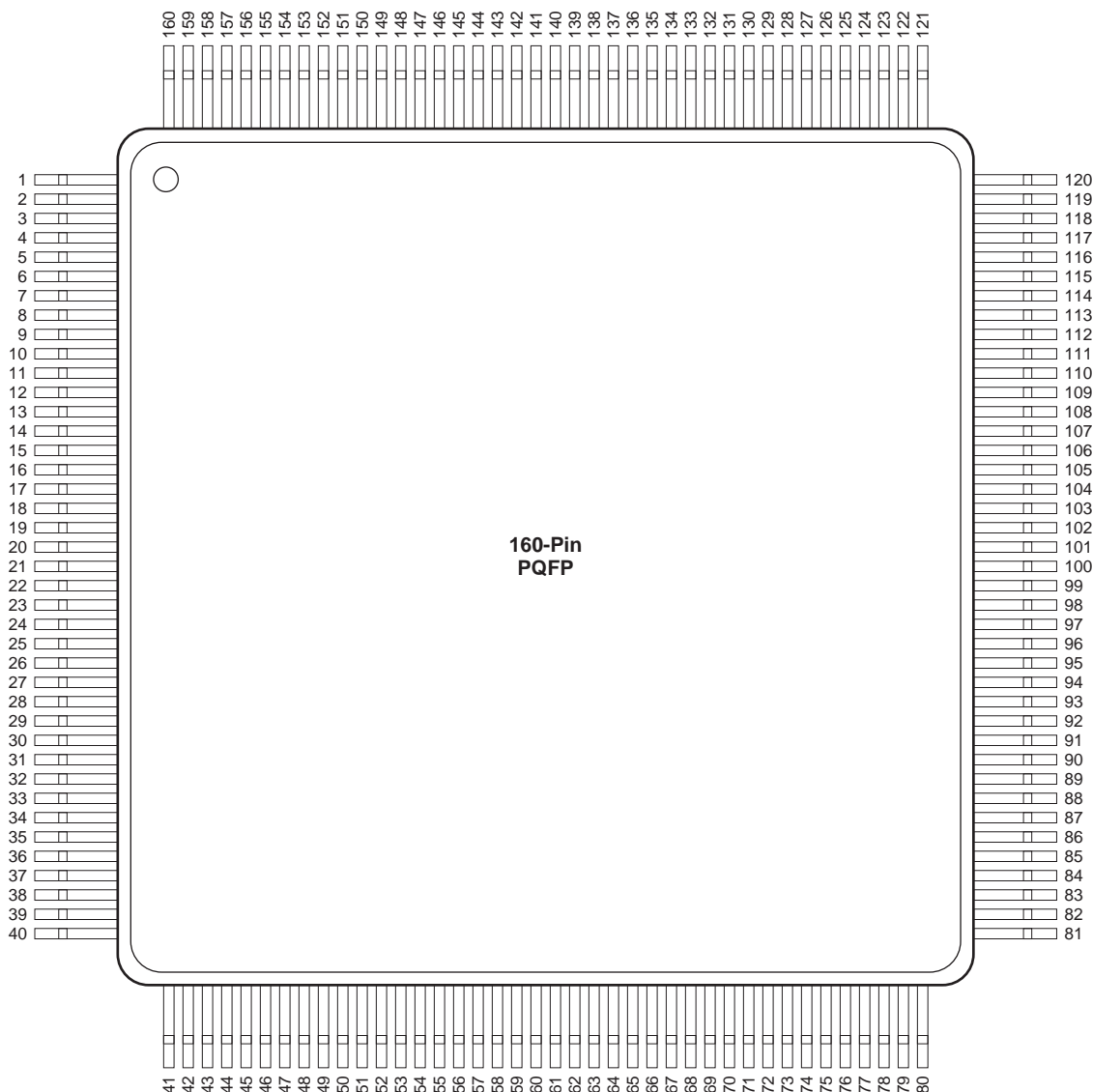
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PQ100		
Pin Number	A1415 Function	A1425 Function
2	IOCLK, I/O	IOCLK, I/O
14	CLKA, I/O	CLKA, I/O
15	CLKB, I/O	CLKB, I/O
16	VCC	VCC
17	GND	GND
18	VCC	VCC
19	GND	GND
20	PRA, I/O	PRA, I/O
27	DCLK, I/O	DCLK, I/O
28	GND	GND
29	SDI, I/O	SDI, I/O
34	MODE	MODE
35	VCC	VCC
36	GND	GND
47	GND	GND
48	VCC	VCC
61	PRB, I/O	PRB, I/O
62	GND	GND
63	VCC	VCC
64	GND	GND
65	VCC	VCC
67	HCLK, I/O	HCLK, I/O
77	SDO	SDO
78	IOPCL, I/O	IOPCL, I/O
79	GND	GND
85	VCC	VCC
86	VCC	VCC
87	GND	GND
96	VCC	VCC
97	GND	GND

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ160



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

CQ196		CQ196	
Pin Number	A1460 Function	Pin Number	A1460 Function
1	GND	101	GND
2	SDI, I/O	110	VCC
11	MODE	111	VCC
12	VCC	112	GND
13	GND	137	VCC
37	GND	138	GND
38	VCC	139	GND
39	VCC	140	VCC
51	GND	148	IOCLK, I/O
52	GND	149	GND
59	VCC	155	VCC
64	GND	162	GND
77	HCLK, I/O	172	CLKA, I/O
79	PRB, I/O	173	CLKB, I/O
86	GND	174	PRA, I/O
94	VCC	183	GND
98	GND	189	VCC
99	SDO	193	GND
100	IOPCL, I/O	196	DCLK, I/O

Notes:

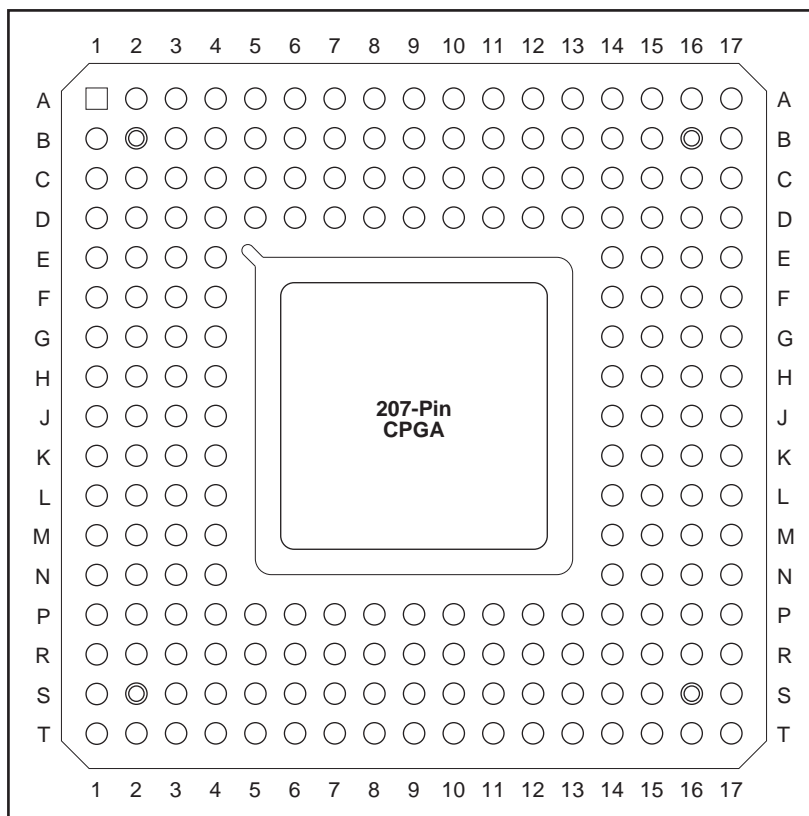
1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

BG225	
A1460 Function	Location
CLKA or I/O	C8
CLKB or I/O	B8
DCLK or I/O	B2
GND	A1, A15, D15, F8, G7, G8, G9, H6, H7, H8, H9, H10, J7, J8, J9, K8, P2, R15
HCLK or I/O	P9
IOCLK or I/O	B14
IOPCL or I/O	P14
MODE	D1
NC	A11, B5, B7, D8, D12, F6, F11, H1, H12, H14, K11, L1, L13, N8, P5, R1, R8, R11, R14
PRA or I/O	A7
PRB or I/O	L7
SDI or I/O	D4
SDO	N13
VCC	A8, B12, D5, D14, E3, E8, E13, H2, H3, H11, H15, K4, L2, L12, M8, M15, P4, P8, R13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The BG225 package has been discontinued.

PG207



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG257	
A14100 Function	Location
CLKA or I/O	L4
CLKB or I/O	L5
DCLK or I/O	E4
GND	B16, C4, D4, D10, D16, E11, J5, K4, K16, L15, R4, T4, T10, T16, T17, X7
HCLK or I/O	J16
IOCLK or I/O	T5
IOPCL or I/O	R16
MODE	A5
NC	E5
PRA or I/O	J1
PRB or I/O	J17
SDI or I/O	B4
SDO	R17
VCC	C3, C10, C13, C17, K3, K17, V3, V7, V10, V17, X14

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

4 – Datasheet Information

List of Changes

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page
Revision 3 (January 2012)	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35820).	2-21
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35820).	3-1
Revision 2 (September 2011)	The ACT 3 datasheet was formatted newly in the style used for current datasheets. The same information is present (other than noted in the list of changes for this revision) but divided into chapters.	N/A
	The datasheet was revised to note in multiple places that speed grades –2 and –3 have been discontinued. The following device/package combinations have been discontinued for all speed grades and temperatures (SAR 33872): A1415 PG100 A1425 PG133 A1440 PG175 A1460 BG225 Refer to PDN 0104 , PDN 0203 , PDN 0604 , and PDN 1004 .	I and others
	The "Features" section was revised to state the clock-to-output time and on-chip performance for –1 speed grade as 9.0 ns and 186 MHz. The "General Description" section was revised in accordance (SAR 33872).	I
	The maximum performance values were updated in Table 1 • ACT 3 Family Product Information , and now reflect worst-case commercial for the –1 speed grade (SAR 33872).	I
	The "Product Plan" table was updated as follows to conform to current offerings (SAR 33872): The A1415A device is offered in PL84, PG100, and VQ100 packages for Military application. The A1440A device is offered in TQ176 and VQ100 packages for Industrial application.	III
	Table 1-1 • Chip-to-Chip Performance (worst-case commercial) was updated to include data for all speed grades instead of only –3 (SAR 33872).	1-2
	Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade) was revised to reflect values for the –1 speed grade (SAR 33872).	1-1
	Figure 2-10 • Timing Model was updated to show data for the –1 speed grade instead of –3 (SAR 33872).	2-16
	Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions was updated to include data for all speed grades instead of only –3 (SAR 33872).	2-20
	Package names used in the "Package Pin Assignments" section and throughout the document were revised to match standards given in Package Mechanical Drawings (SAR 27395).	3-1